

RoHS

KF7N65FM-VB Datasheet

N-Channel 650V (D-S) Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V) at T _J max.	650				
R _{DS(on)} at 25 °C (Ω)	$V_{GS} = 10 V$	1.1			
Q _g max. (nC)	25				
Q _{gs} (nC)	2.0				
Q _{gd} (nC)	2.7				
Configuration	Single				

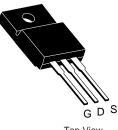
FEATURES

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Q_q)
- Avalanche energy rated (UIS)

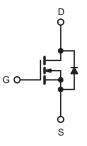
APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
- Fluorescent ballast lighting
- Industrial

TO-220 FULLPAK



Top View



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T $_{\rm C}$:	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	650	V	
Gate-Source Voltage			V _{GS}	± 30	V	
Continuous Drain Current (T, = 150 °C)	V at 10 V	T _C = 25 °C T _C = 100 °C	1	7.0		
Continuous Drain Current $(I_J = 150 \text{ C})$	V _{GS} at 10 V	T _C = 100 °C		5.6	A	
Pulsed Drain Current ^a			I _{DM}	28		
Linear Derating Factor				1.67/1.5/0.3	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	86	mJ	
Maximum Power Dissipation			P _D	83/83/31	W	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C	
Drain-Source Voltage Slope $T_J = 125 \text{ °C}$		al\ / / alt	50			
Reverse Diode dV/dt ^d			dV/dt	4.5	V/ns	
Soldering Recommendations (Peak Temperature) ^c	for	10 s		300	°C	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. V_{DD} = 50 V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 3.5 A.

c. 1.6 mm from case. d. $I_{SD} \le I_D$, dl/dt = 100 A/µs, starting $T_J = 25$ °C.



THERMAL RESISTANCE RAT	INGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	63	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.6	0/10

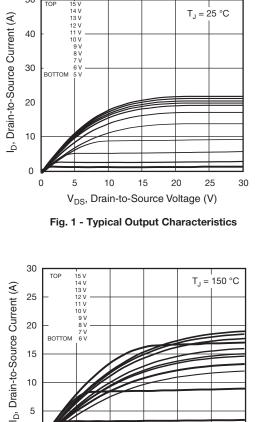
PARAMETER	SYMBOL	TES	F CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static				•	•		
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D = 250 μA	650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2.5	-	5	V
		,	$V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 30 V	-	-	± 1	μA
			= 650 V, V _{GS} = 0 V	-	-	1	-
Zero Gate Voltage Drain Current	I _{DSS}		′, V _{GS} = 0 V, T _J = 125 °C	-	-	10	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	$I_D = 4 A$	-	1.1	-	Ω
Forward Transconductance	g _{fs}		= 30 V, I _D = 4 A	-	16	-	S
Dynamic		•		1	1	1	
Input Capacitance	C _{iss}		V _{GS} = 0 V,	-	860	-	
Output Capacitance	C _{oss}	-	$V_{GS} = 0 V,$ $V_{DS} = 100 V,$		120	-	1
Reverse Transfer Capacitance	C _{rss}	-	f = 1 MHz	-	15	-	1
Effective Output Capacitance, Energy Related ^a	C _{o(er)}			-	45	-	pF
Effective Output Capacitance, Time Related ^b	C _{o(tr)}	- V _{DS} = 0 V	V to 520 V, V _{GS} = 0 V	-	62	-	
Total Gate Charge	Qg			-	25		
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 V$	$I_D = 4 \text{ A}, V_{DS} = 520 \text{ V}$	-	2.0	-	nC
Gate-Drain Charge	Q _{gd}			-	2.7	-	
Turn-On Delay Time	t _{d(on)}			-	25	-	
Rise Time	t _r	Voo	= 520 V. In = 4 A.	-	55	-	nc
Turn-Off Delay Time	t _{d(off)}	20		-	ns		
Fall Time	t _f			-	40	-	1
Gate Input Resistance	R _g	f = 1	MHz, open drain	-	3.5	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the		-	-	7	
Pulsed Diode Forward Current	I _{SM}	integral revers p - n junction		-	-	18	A
Diode Forward Voltage	V _{SD}	T _J = 25 °	C, I _S = 4 A, V _{GS} = 0 V	-	-	1.5	V
Reverse Recovery Time	t _{rr}			-	190	-	ns
Reverse Recovery Charge	Q _{rr}	$T_J = 2$	5 °C, $I_F = I_S = 4 \text{ A}$,	-	2.3	-	μC
Reverse Recovery Current	I _{RRM}	ai/dt = 1	00 A/µs, V _R = 400 V	_	10	_	A

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .

50





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

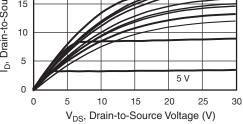


Fig. 2 - Typical Output Characteristics

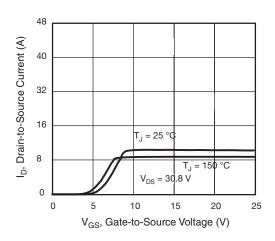


Fig. 3 - Typical Transfer Characteristics

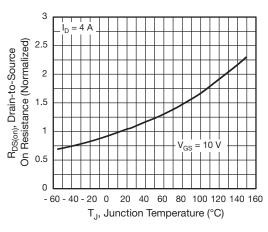


Fig. 4 - Normalized On-Resistance vs. Temperature

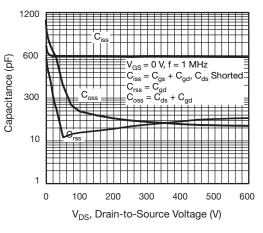


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



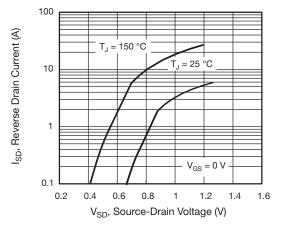


Fig. 7 - Typical Source-Drain Diode Forward Voltage



Fig. 8 - Maximum Safe Operating Area



Fig. 9 - Maximum Drain Current vs. Case Temperature



Fig. 10 - Temperature vs. Drain-to-Source Voltage



Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



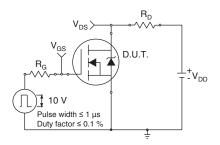


Fig. 12 - Switching Time Test Circuit

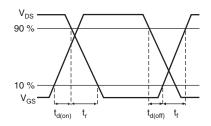


Fig. 13 - Switching Time Waveforms

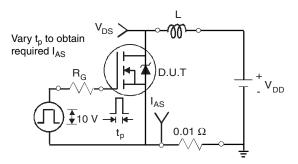


Fig. 14 - Unclamped Inductive Test Circuit



Fig. 15 - Unclamped Inductive Waveforms

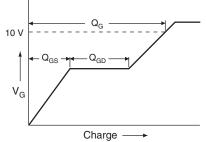


Fig. 16 - Basic Gate Charge Waveform

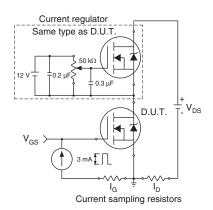
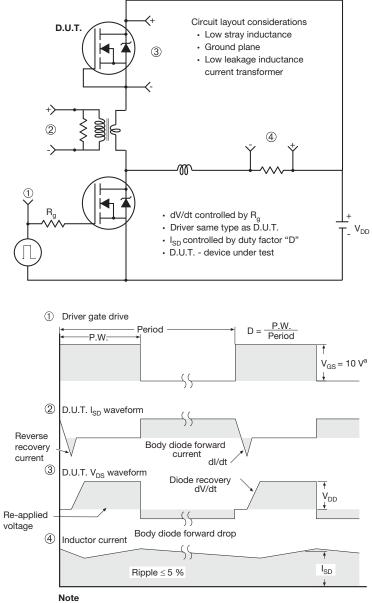


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

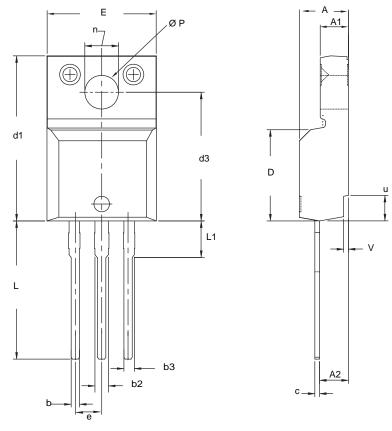


a. $V_{GS} = 5 \text{ V}$ for logic level devices

Fig. 18 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)



	MILLI	METERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
А	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100	BSC
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØP	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

Notes

1. To be used only for process drawing. 2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads. 3. All critical dimensions should C meet $C_{pk} > 1.33$. 4. All dimensions include burrs and plating thickness.

5. No chipping or package damage.



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